Notice of References Cited 10/830,069 Examiner Erma Cameron Reexamination ENDO ET AL. Page 1 of 1

Application/Control No.

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-4,155,767	05-1979	Specht et al.	106/31.06
	В	US-6,372,154	04-2002	Li, Xiao-Chang Charles	252/301.16
-	С	US-6,825,061	11-2004	Hokari et al.	438/99
	D	US-6,878,312	04-2005	Kanbe et al.	252/583
	E	US-			
	F	US-			
	G	US-			
	Н	US-			
	1	US-			
	J	US-			
	К	US-		·	
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	EP 892028	01-1999	EP	Seiko Epson	-
	0	JP 2004-179144	06-2004	JP	Seiko Epson	-
	Р					*
	Q					
	R					
	s					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Shimoda et al, Int. Electron Devitces Meeting, pp 107-110, 1999
	٧	
	w	
	x	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Applicant(s)/Patent Under